Sheet 1 of 1

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

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Application Number	10/544,703	
Filing Date	October 9, 2006	
First Named Inventor	Susanne Lang-Fugmann	
Art Unit	4161	
Examiner Name	Tigabu Kassa	
Attorney Docket No.	9741-014-999	

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EXAMINER SIGNATURE

DATE CONSIDERED

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